

#### **Description**

The AP120N10NF uses advanced APM-SGTII technology to provide excellent R<sub>DS(ON)</sub>, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

#### **General Features**

 $V_{DS} = 100V I_{D} = 120A$ 

 $R_{DS(ON)} < 4.5 \text{m}\Omega$  @  $V_{GS}=10 \text{V}$  (Type: 3.8 m $\Omega$ )

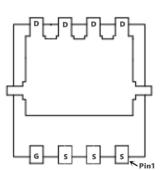
#### **Application**

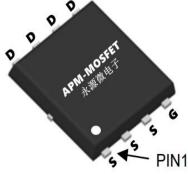
Isolated DC

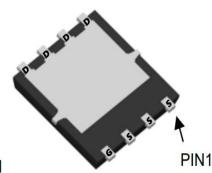
Motor control

Synchronous-rectification









**Package Marking and Ordering Information** 

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Product ID	Pack	Marking	Qty(PCS)	
AP120N10NF	PDFN5*6-8L	AP120N10NF XXX YYYY	5000	

#### Absolute Maximum Ratings (T<sub>C</sub>=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	100	V
VGS	Gate-Source Voltage	±20	V
I <sub>D</sub> @T <sub>A</sub> =25°C	Continuous Drain Current <sup>1</sup>	120	Α
I <sub>D</sub> @T <sub>A</sub> =70°C	Continuous Drain Current <sup>1</sup>	76	Α
IDM	Pulsed Drain Current <sup>2</sup>	480	А
EAS	Single Pulse Avalanche Energy <sup>3</sup>	320	mJ
IAS	Avalanche Current	40	А
P <sub>D</sub> @T <sub>A</sub> =25°C	Total Power Dissipation <sup>4</sup>	131.6	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R₀JA	Thermal Resistance Junction-Ambient <sup>1</sup>	25	°C/W
R₀JC	Thermal Resistance Junction-Case <sup>1</sup>	0.95	°C/W







#### Electrical Characteristics (T<sub>c</sub>=25 ℃ unless otherwise noted)

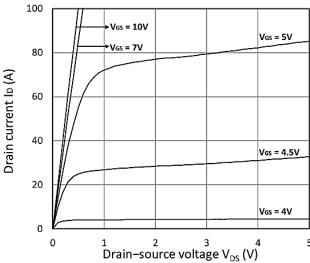
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	100	107	1	V
IGSS	Gate-body Leakage current	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	-	-	±100	nA
IDCC	Zero Gate Voltage Drain Current T <sub>J</sub> =25°C	\/ -400\/ \/ - 0\/	-	-	1	
IDSS	Zero Gate Voltage Drain Current T <sub>J</sub> =100°C	$V_{DS} = 100V, V_{GS} = 0V$	-	-	100	μA
VGS(th)	Gate-Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0	3.0	4.0	V
RDS(on)	Drain-Source on-Resistance <sup>4</sup>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A	-	3.8	4.5	mΩ
gfs	Forward Transconductance <sup>4</sup>	V <sub>DS</sub> = 10V, I <sub>D</sub> = 20A	-	62	-	S
Ciss	Input Capacitance	V <sub>DS</sub> = 50V, V <sub>GS</sub> =0V, f =1MHz	-	6865	-	pF
Coss	Output Capacitance		-	740	-	
Crss	Reverse Transfer Capacitance	1 11/11/2	-	21	-	
$R_g$	Gate Resistance	f =1MHz	-	1.3	-	Ω
$Q_g$	Total Gate Charge		-	111.2	-	
Qgs	Gate-Source Charge	$V_{GS} = 10V, V_{DS} = 50V,$ $I_{D}=20A$	-	30.5	-	nC
Qgd	Gate-Drain Charge	15 25/1	-	27.3	-	
td(on)	Turn-on Delay Time		-	33	-	
tr	Rise Time	V <sub>GS</sub> =10V, V <sub>DD</sub> =50V, R <sub>G</sub> =	-	39	-	no
td(off)	Turn-off Delay Time	3Ω, I <sub>D</sub> = 20A	-	67.1	-	ns
t <sub>f</sub>	Fall Time		-	32	-	
trr	Body Diode Reverse Recovery Time	I <sub>F</sub> = 20A, dl/dt=100A/μs	_	58.7	-	ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge		-	97.3	-	nC
VSD	Diode Forward Voltage <sup>4</sup>	I <sub>S</sub> = 20A, V <sub>GS</sub> = 0V	-	-	1.2	V
IS	Continuous Source Current Tc=25°C	-	-	-	120	Α

#### Note

- 1. The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- $2\sqrt{100}$  The data tested by pulsed , pulse width  $\leqq 300us$  , duty cycle  $\leqq 2\%$
- $3\$  The EAS data shows Max. rating . The test condition is VDD=72V,VGS=10V, L=0.1mH IAS=40A
- 4. The power dissipation is limited by 150°C junction temperature
- 5. The data is theoretically the same as I D and I DM , in real applications , should be limited by total power dissipation



# **Typical Characteristics**



**Figure 1. Output Characteristics** 

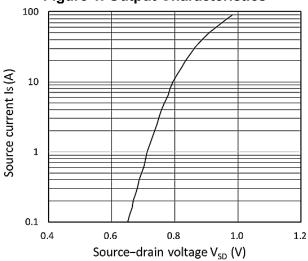


Figure 2. Transfer Characteristics

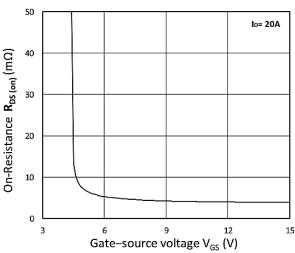


Figure 3. Forward Characteristics of Reverse

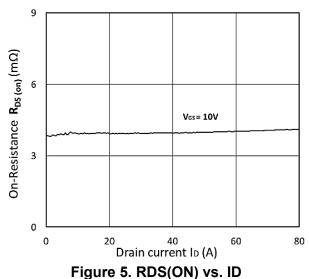


Figure 4. RDS(ON) vs. VGS

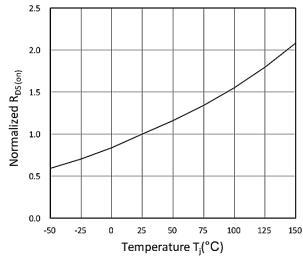


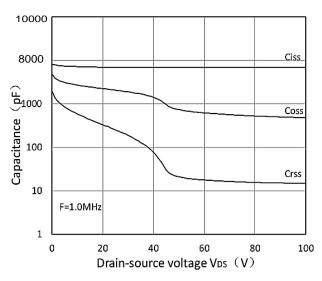
Figure 6. No

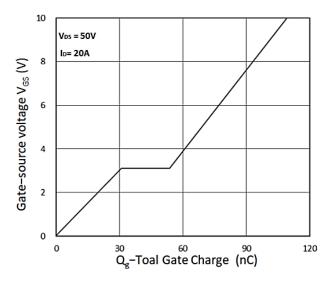
Figure 6. Normalized RDS(on) vs. Temperature





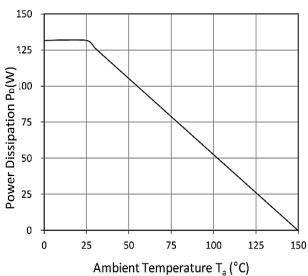






**Figure 7. Capacitance Characteristics** 





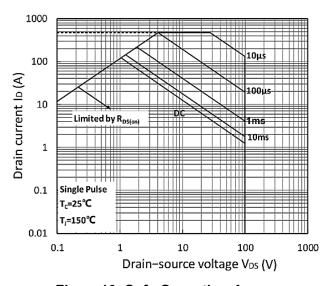


Figure 9. Power Dissipation

Figure 10. Safe Operating Area

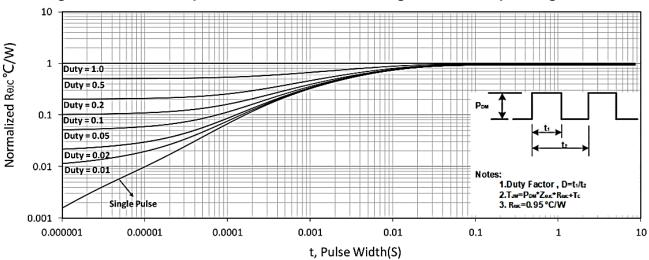
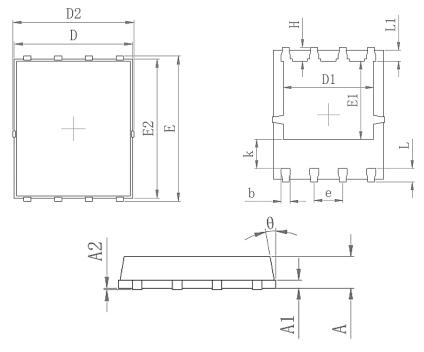


Figure 11. Normalized Maximum Transient Thermal Impedance

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# Package Mechanical Data-PDFN5X6-8L-XZT Single



	Com	mon	
Symbol	mm		
	Mim	Max	
A	0.90	1.10	
A1	0.254	I REF	
A2	0-0.	.05	
D	4.824	4.976	
D1	3.910	4.110	
D2	4.944	5.076	
E	5.924	6.076	
E1	3.375	3.575	
E2	5.674	5.826	
b	0.350	0.450	
е	1.270		
L	0.534	0.686	
L1	0.424	0.576	
K	1.190	1.390	
Н	0.549	0.701	
Ф	8°	12°	





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# **AP120N10NF**

## **100V N-Channel Enhancement Mode MOSFET**

Edition	Date	Change
Rve1.0	2021/1/31	Initial release

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